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SPECIALLY DESIGNED TO SCAN HIGH ASPECT RATIO AND DENSE STRUCTURES ON SAMPLE SURFACES

Highlights

- Customization**
Available for various tip shapes, coatings and dimensions.
- Affordability**
Affordable tips that provide high quality images.
- Compatibility**
Compatible with all AFM's on the market.

High Resolution

The HAR probe consists of a high aspect ratio pillar on the apex of the pyramid. This probe produces an accurate high-resolution AFM image.

NDS' high aspect ratio AFM tips can be used to image small, and complex features with the highest image quality and the best price in the market. HAR probe is best suited for the force modulation measurements.

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